

BUK78150-55A-VB Datasheet N-Channel 60-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)			
60	0.076 at V _{GS} = 10 V	4.5	10 nC			
	0.085 at V _{GS} = 4.5 V	3.5	TOTIC			

FEATURES

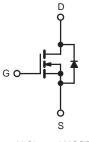
- · Halogen-free
- Trench Power MOSFET

APPLICATIONS

· Load Switches for Portable Devices







N-Channel MOSFET

Parameter Drain-Source Voltage Gate-Source Voltage		Symbol	Limit	Unit	
		V _{DS}	60 ± 20	V	
		V _{GS}			
	T _C = 25 °C		4.5		
Continuous Drain Current ($T_1 = 150 \ ^{\circ}C$)	T _C = 70 °C	1-	3.2 ^a		
Continuous Drain Current (1) = 150°C)	T _A = 25 °C		2.7		
	T _A = 70 °C		2.3	A	
Pulsed Drain Current		I _{DM}	20		
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	3.2		
Continuous Source-Drain Diode Current	T _A = 25 °C	'5	2.1 ^{b, c}		
	T _C = 25 °C		4.0		
Maximum Power Dissipation	T _C = 70 °C	P _D	3.0	w	
Maximum Fower Dissipation	T _A = 25 °C		2.5 ^{b, c}	VV	
	T _A = 70 °C		1.6 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	℃	
Soldering Recommendations (Peak Temperature) ^{e, f}			260	- C	

THERMAL RESISTANCE BATINGS

Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{a, c, d}	t ≤ 5 s	R _{thJA}	40	50	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	15	20	0/11		

Notes:

a. Package limited, T_C = 25 °C.
b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under Steady State conditions is 95 °C/W.

e. See Reliability Manual for profile. The ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.

f. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.

SPECIFICATIONS $T_J = 25 \text{ °C}$, Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	Symbol	Test conditions	IVIIII.	Typ.	Iviax.	Onic
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	60			V
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J			25		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 4.0		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 250 \ \mu A$	1.0	4.0	2.5	V
Gate-Source Leakage	· ·	$V_{DS} = 0 V, V_{GS} = \pm 12 V$	1.0		± 100	nA
Gale-Source Leakage	I _{GSS}	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$			± 100	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 60 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 \text{ °C}$			10	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 V, V_{GS} = 4.5 V$	30			Α
		V _{GS} = 10 V , I _D = 4.0 A		0.076		Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 3.0 A		0.085		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 10 V, I _D = 4.0 A		45		S
Dynamic ^b			I			
Input Capacitance	C _{iss}			810		
Output Capacitance	C _{oss}	V _{DS} = 30V [,] V _{GS} = 0 V, f = 1 MHz		120		pF
Reverse Transfer Capacitance	C _{rss}			100		
-		V _{DS} = 30 V, V _{GS} = 10 V, I _D = 4.0 A		22	33	nC
Total Gate Charge	Qg			10	15	
Gate-Source Charge	Q _{gs}	V _{DS} = 30 V, V _{GS} = 4.5 V, I _D = 3.0 A		2.5		
Gate-Drain Charge	Q _{gd}			1.7		
Gate Resistance	R _g	f = 1 MHz		2.4		Ω
Turn-on Delay Time	t _{d(on)}			15	25	
Rise Time	t _r	$V_{DD} = 30V, R_{I} = 1.5 \Omega$		10	15	-
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 4.0 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		35	55	
Fall Time	t _f			12	20	
Turn-on Delay Time	t _{d(on)}			10	15	ns
Rise Time	t _r	V_{DD} = 30V , R_{L} = 1.5 Ω		12	20	-
Turn-Off Delay Time	t _{d(off)}	${ m I}_{ m D}\cong$ 4.0 A, ${ m V}_{ m GEN}$ = 10 V, ${ m R}_{ m g}$ = 1 Ω		25	40	
Fall Time	t _f			10	15	
Drain-Source Body Diode Characteristic	s		Ι		•	
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			7.2	٨
Pulse Diode Forward Current	I _{SM}				30	A
Body Diode Voltage	V _{SD}	$I_{S} = 4.0 \text{ A}, V_{GS} = 0 \text{ V}$		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			20	40	ns
Body Diode Reverse Recovery Charge	Q _{rr}	Q.,		10	20	nC
Reverse Recovery Fall Time	ta	$I_F = 4.0 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^\circ\text{C}$		10		ns
Reverse Recovery Rise Time	t _b			10		

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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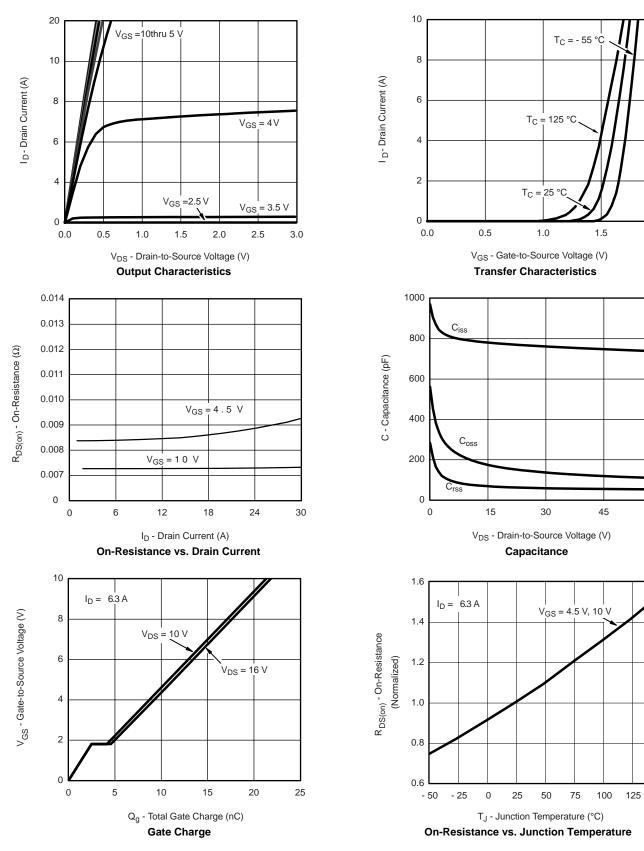
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2.0

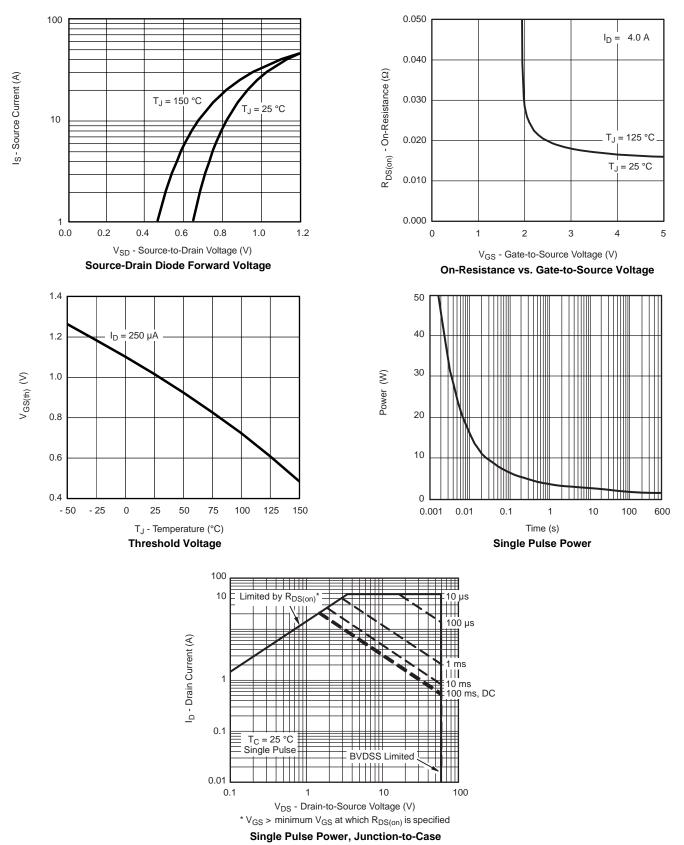
60

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



服务热线:400-655-8788

150

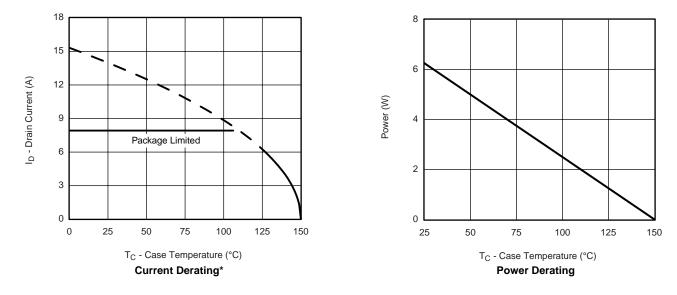


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

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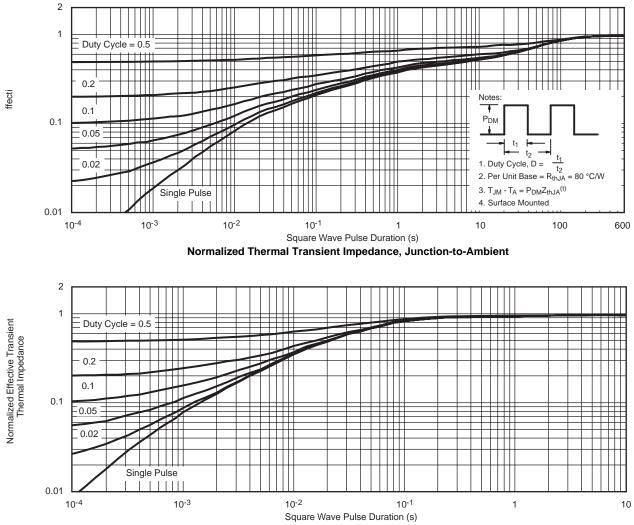


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



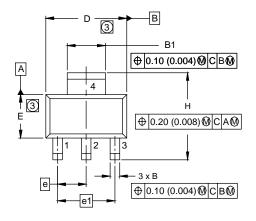
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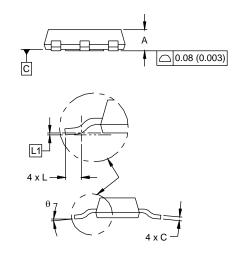


Normalized Thermal Transient Impedance, Junction-to-Foot



SOT-223 (HIGH VOLTAGE)





DIM.	MILLI	METERS	INCHES		
	MIN.	MAX.	MIN.	MAX.	
А	1.55	1.80	0.061	0.071	
В	0.65	0.85	0.026	0.033	
B1	2.95	3.15	0.116	0.124	
С	0.25	0.35	0.010	0.014	
D	6.30	6.70	0.248	0.264	
E	3.30	3.70	0.130	0.146	
е	2.30 BSC		0.0905 BSC		
e1	4.60 BSC		0.181 BSC		
Н	6.71	7.29	0.264	0.287	
L	0.91	-	0.036	-	
L1	0.061 BSC		0.002	4 BSC	
θ	-	10'	-	10'	

Notes

1. Dimensioning and tolerancing per ASME Y14.5M-1994.

2. Dimensions are shown in millimeters (inches).

3. Dimension do not include mold flash.

4. Outline conforms to JEDEC outline TO-261AA.



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